Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/532,443	HACKETT, DAVID	
Examiner	Art Unit	
Chuck Mah	3677	

Chuck Mah

SEARCHED				
Class	Subclass	Date	Examiner	
16	20-2	2		
	25-2	7		
	38			
	31A			
	43			
(88	1.12	*		
280	79.11			
411	79.2			
	34	9/30/06	an	
248	349.1			
	223.41			
	546.11			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		